

IN THE SPECIFICATION:

Please replace the following paragraphs as shown below:

Please substitute the second paragraph on page 1, lines 14-22 with the following:

Published International Application WO 00/17909 (PCT/AU99/00766) discloses The subject disclosure refers to a mass spectrometer having an ion reflecting instead of or an ion transmissive optics system. The spectrometer includes an ion source for providing a supply of particles including ions representative of chemical elements present in an analytical sample and an ion optics system between the ion source and a mass analyzer for producing a beam of ions from the source and establishing a reflecting electrostatic field for reflecting ions from the beam through an angle, for example 90⁰, and for focussing them into the mass analyzer entrance.

Please substitute the following for the third paragraph starting on page 1, lines 24-34 and ending on page 2, lines 1-2.

It has been found that the present invention of WO 00/17909 as embodied in an ICP-MS instrument gives excellent sensitivity for detection of elemental isotopes having relatively high atomic masses (for example, the sensitivity for thorium, atomic mass 232, was over 650,000 counts per second per microgram per litre). However the sensitivity for elemental isotopes having low atomic masses is relatively poor (for example the sensitivity for beryllium, atomic mass 9, was less than 10,000 counts per second per microgram per litre). Furthermore, the background count rate (the count rate detected at a selected mass-to-charge ratio when no ions having that selected mass-to-charge ratio where expected to be present) was higher than desired, and when the voltages applied to the ion optics electrodes were increased to improve the focussing to increase sensitivity for detection of low atomic mass isotopes, the background count rate unfavourably increased.

Please delete the third paragraph on page 5, lines 20-24.